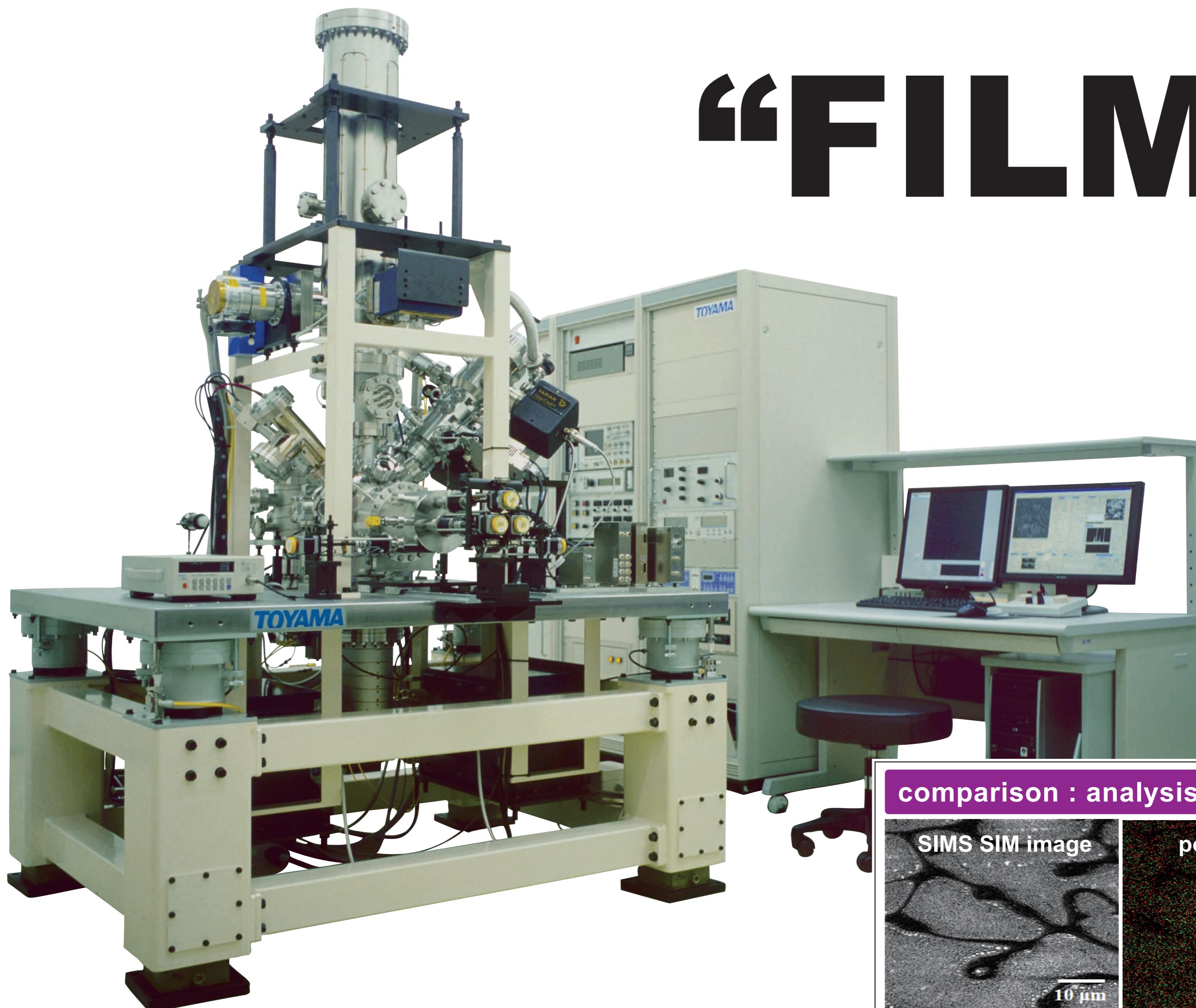


FIB Laser Ionized nano Mass Imager

“FILMER”



Key Features:

1. High Spatial resolution

using the optimized Ga-FIB

- lateral resolution < 40nm
- mass resolution $m/\Delta m > 7000@m/z=56$

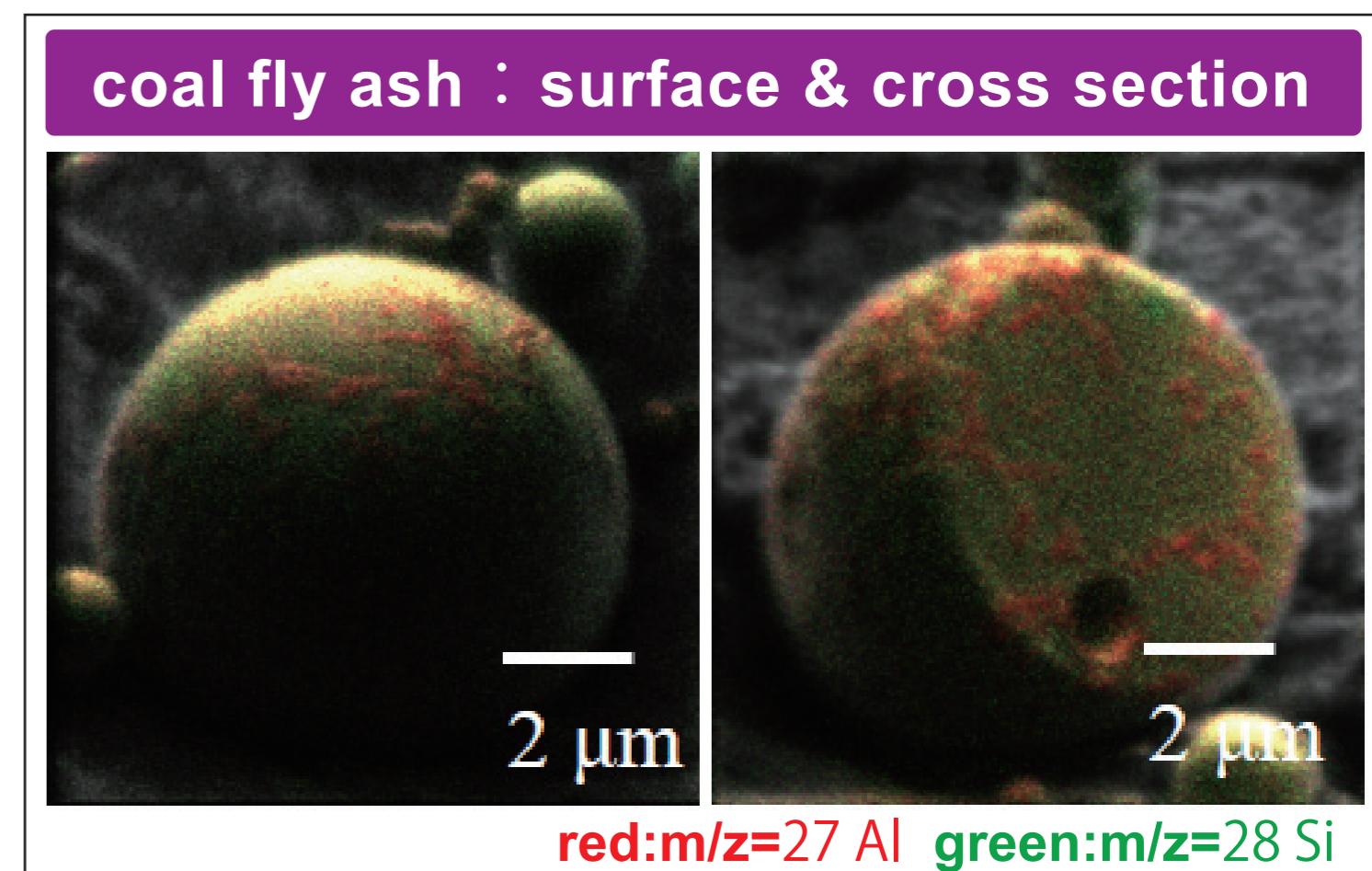
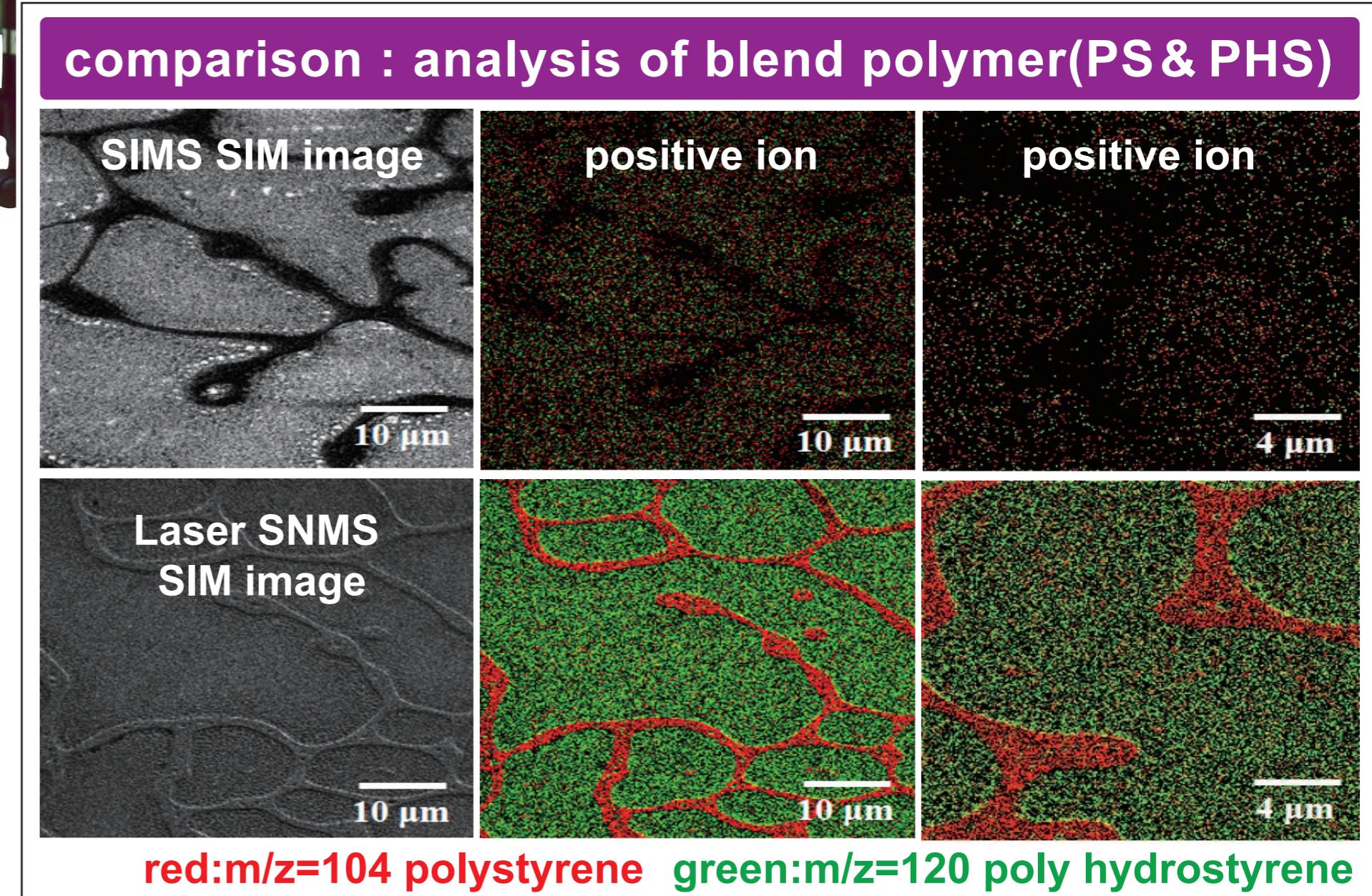
2. Machining and Analysis are

available *in-situ* without air exposure

- little damage observation by SEM directed at the same position as FIB
- possible to analyze both the surface and cross section of a particle

3. Laser SNMS is available

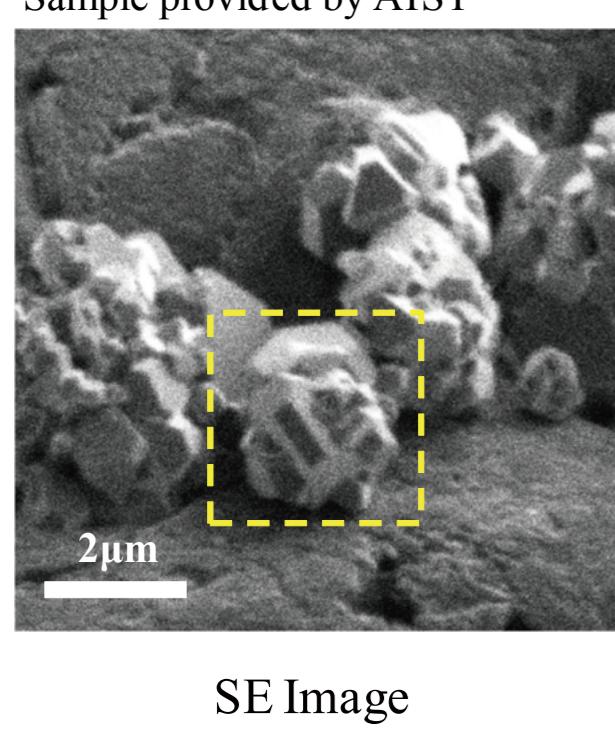
- significant improvement of the signal sensitivity compared to the conventional SIMS
- high sensitive analysis for organic compound



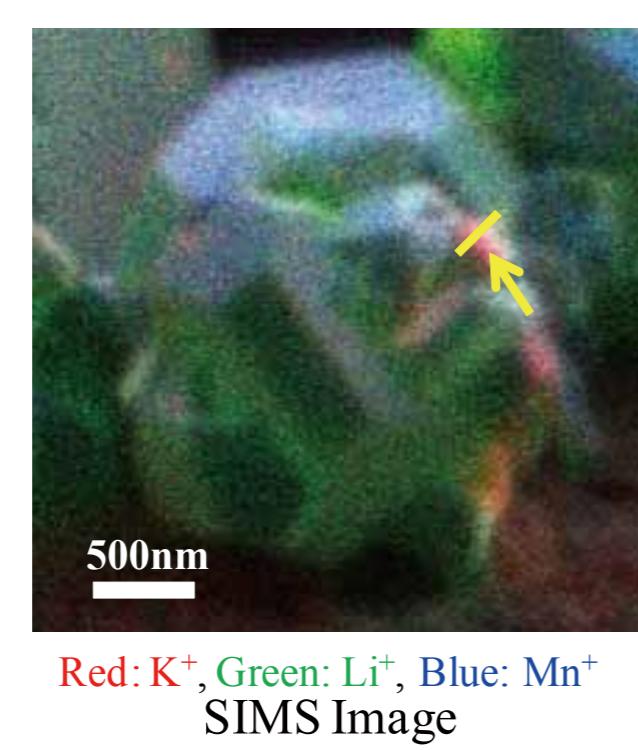
Compatibility between High Lateral Resolution and Mass Resolution

Li Ion Battery(positive electrode)

*Sample provided by AIST

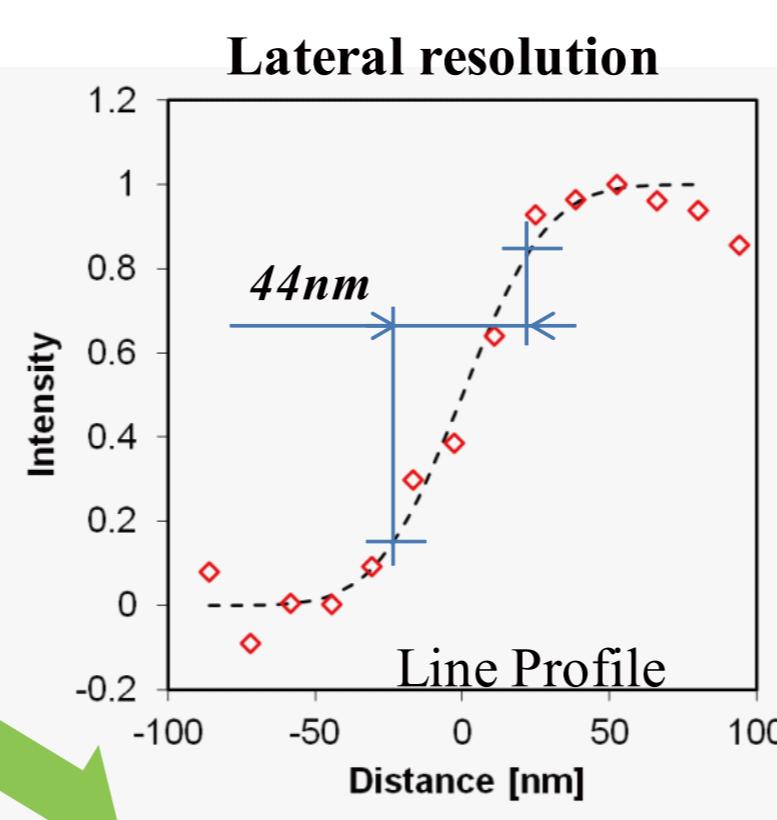


SE Image

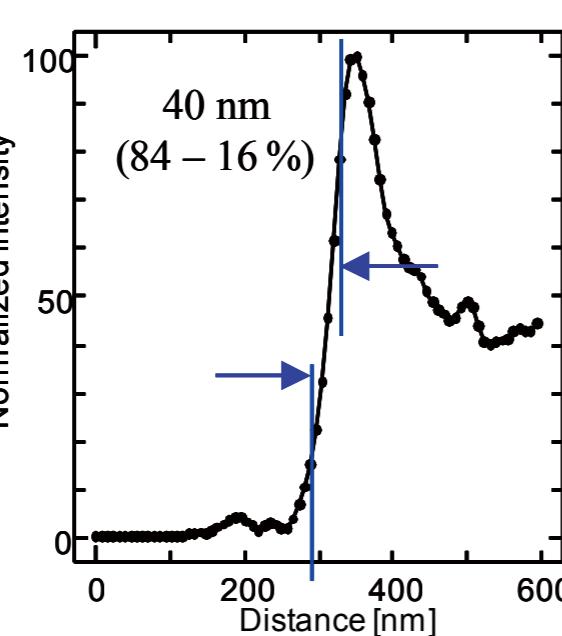
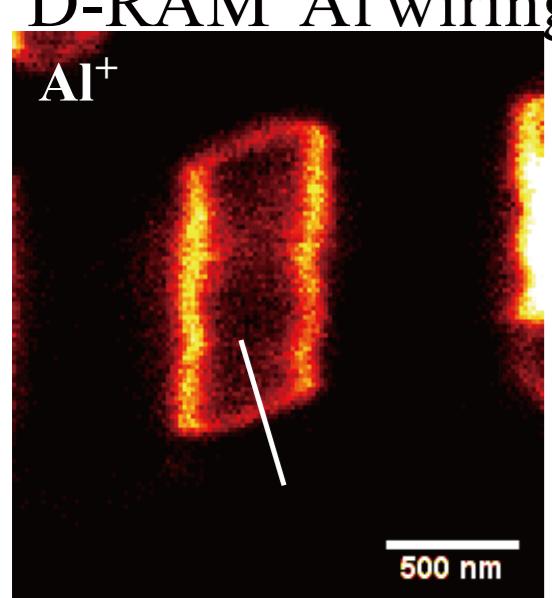


Red: K⁺, Green: Li⁺, Blue: Mn⁺
SIMS Image

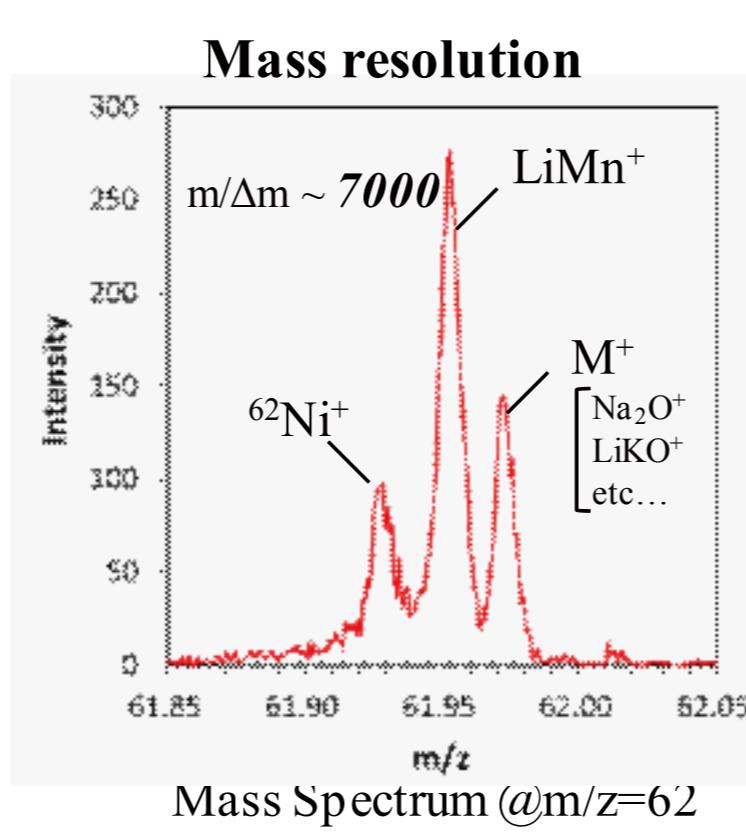
*FIB current: 60pA
Measurement time: 69 minutes



Cross section of D-RAM Al wiring

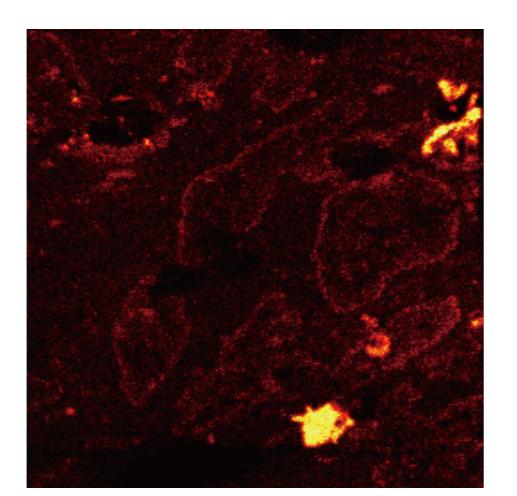


Ref) T. Sakamoto et. all,
Applied Surface Science, 2008, 255, 1617.

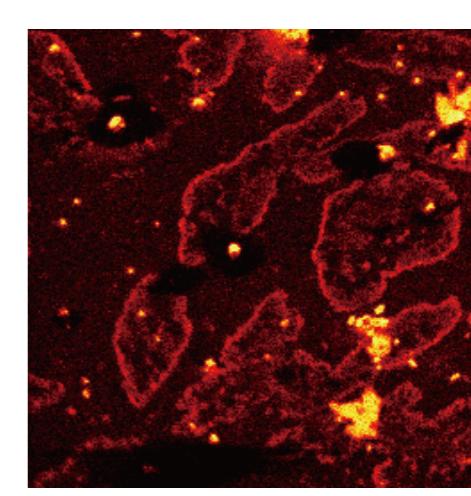


Suspended Particulate Matter (PM_{2.5})

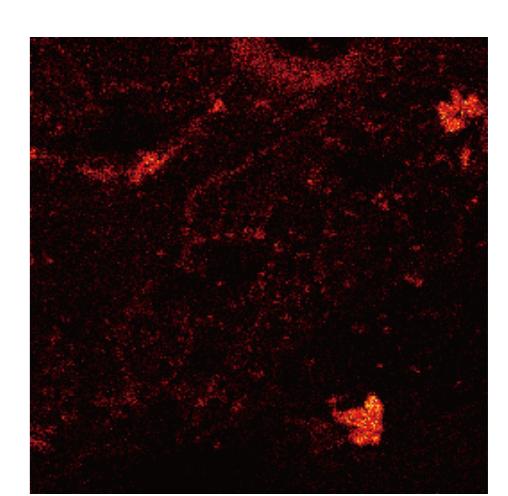
Positive Ion (FoV 50μm)



m/z=23 Na

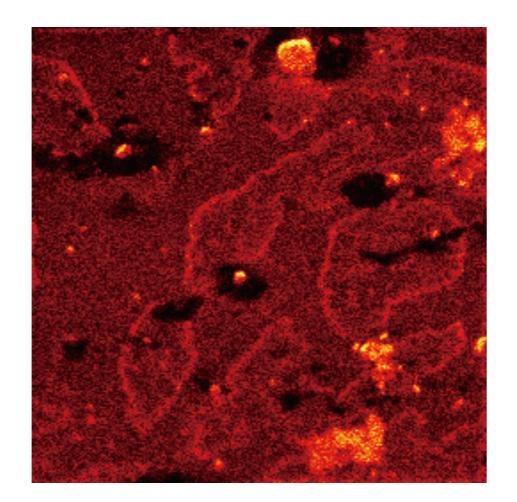


m/z=39 K

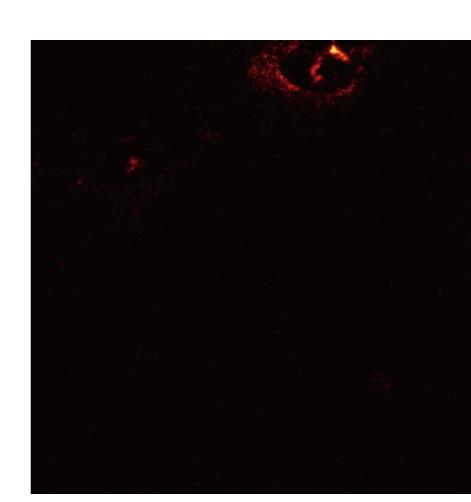


m/z=40 Ca

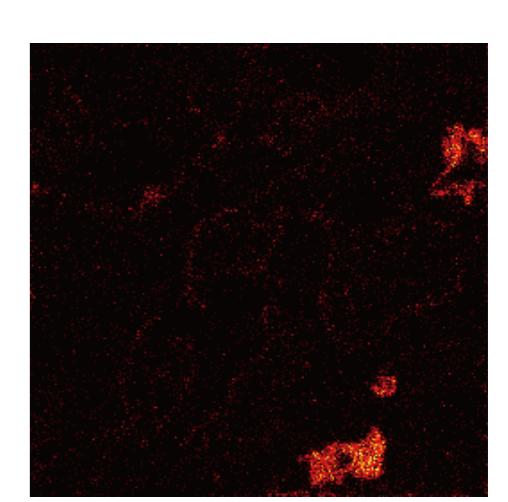
Negative Ion (FoV 50μm)



m/z=16 O



m/z=35 Cl

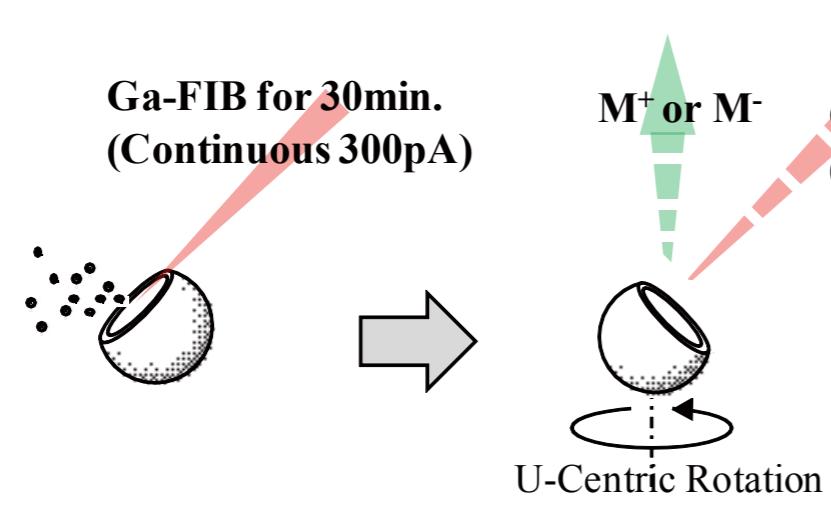
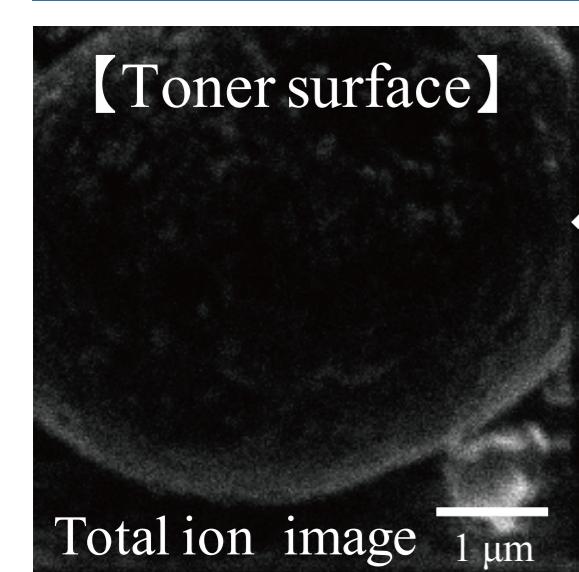


m/z=63 PO₂

*Collected near TOYAMA, R&D Center

Collected on Si-wafers set on poly carbonate filter in PM_{2.5} standard sampler

FIB Fine Processing can Extend the subject to be Analyzed.



Detection of metal oxides from the surface (charge-controlling agents, migration-controlling agents)

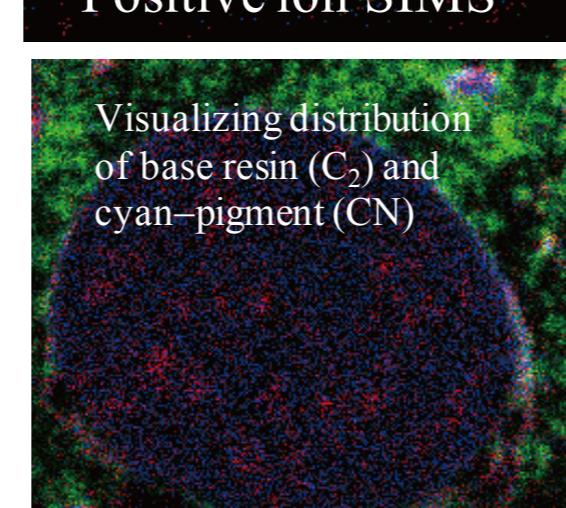
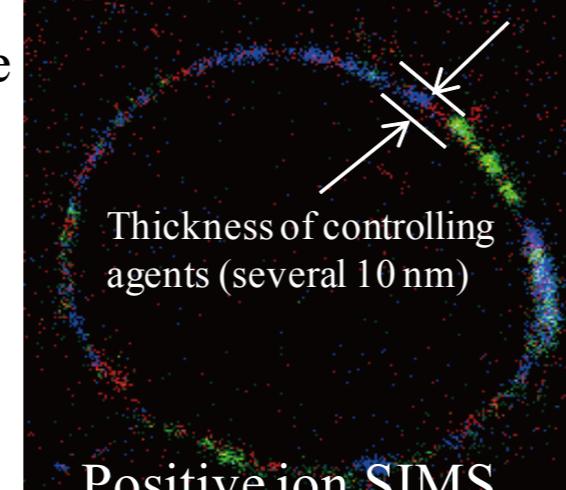
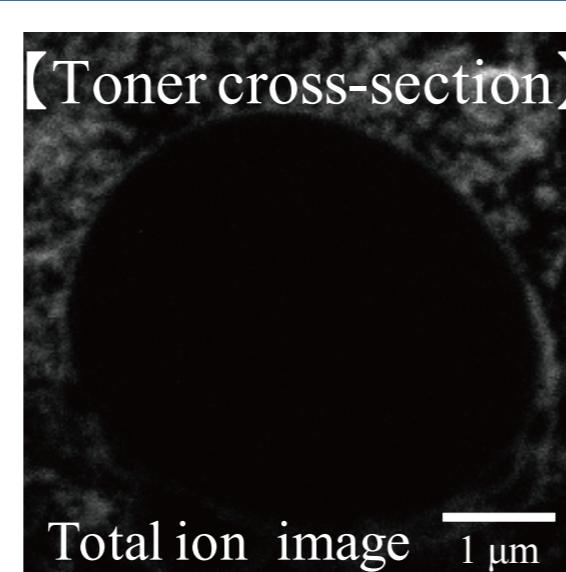
Red; m/z = 27 Al⁺
Green; m/z = 28 Si⁺
Blue; m/z = 48 Ti⁺

Red; m/z = 26 CN⁻
=>Fragment of Cu-Phthalocyanine (cyan-pigment)
Green; m/z = 16 O⁻
=>Distribution of oxygen and metal ions are identical
Blue; m/z = 24 C₂⁻
=>Signals from base resin and wax

Total ion image 1 μm

Positive ion SIMS

Negative ion SIMS

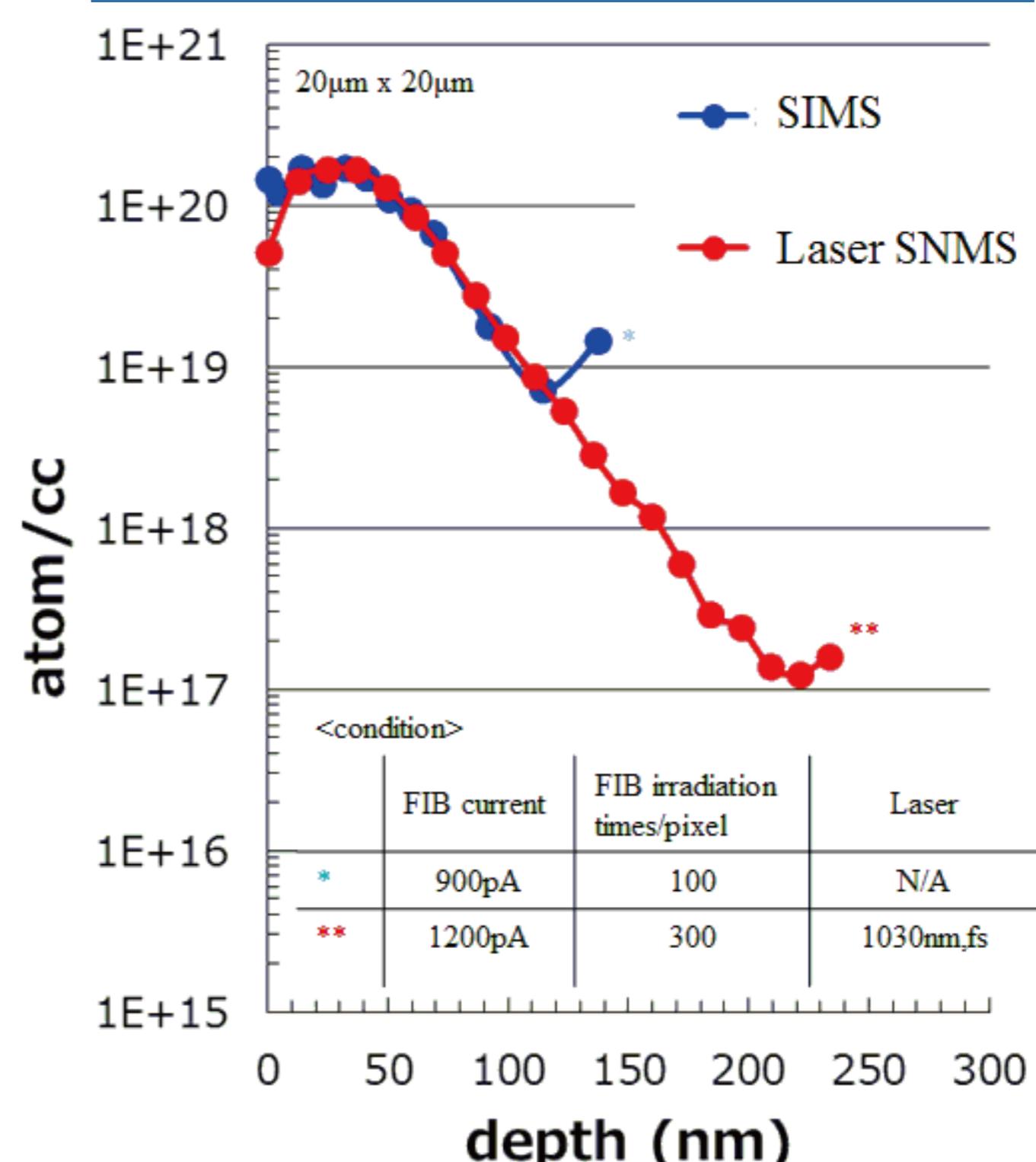


Total ion image 1 μm

Positive ion SIMS

Negative ion SIMS

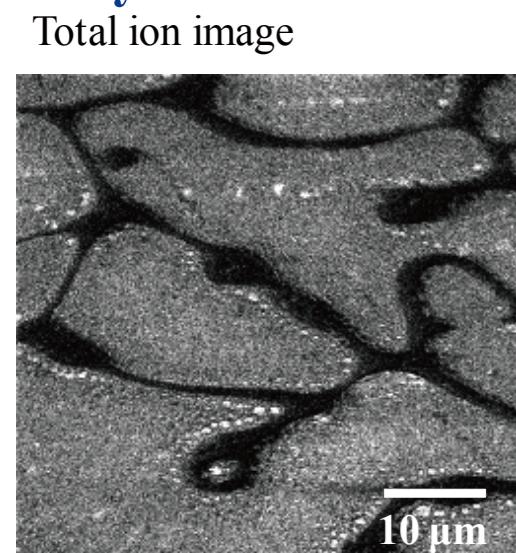
B-Doped Semiconductor



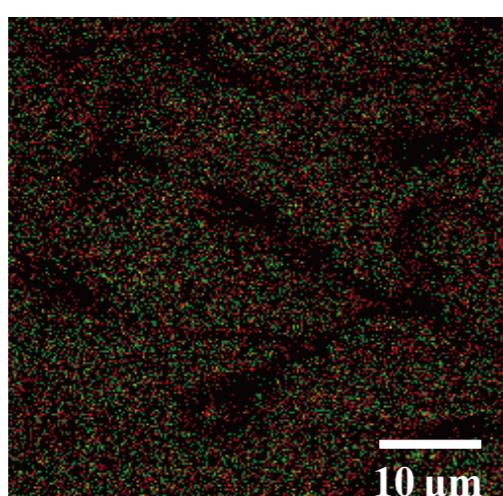
Practical Example of Laser SNMS on Polymer

Nano scale mapping of phase separated structure of organic polymer mixture.

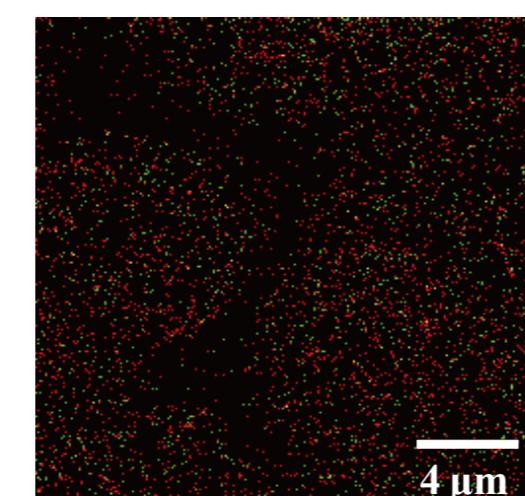
SIMS analysis Positive ion mode



Total ion image

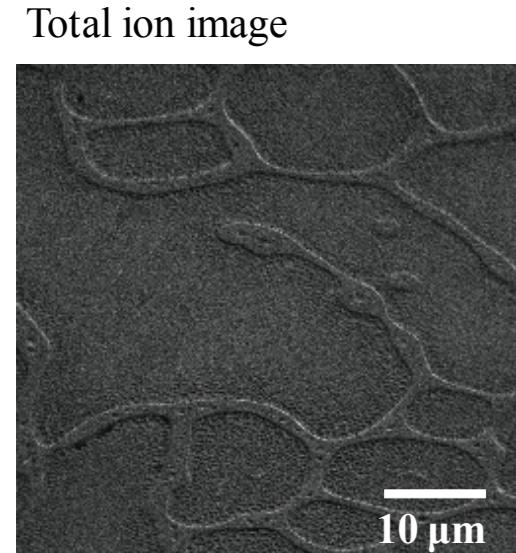


Red; m/z = 91 PS, Green; m/z = 107 PHS

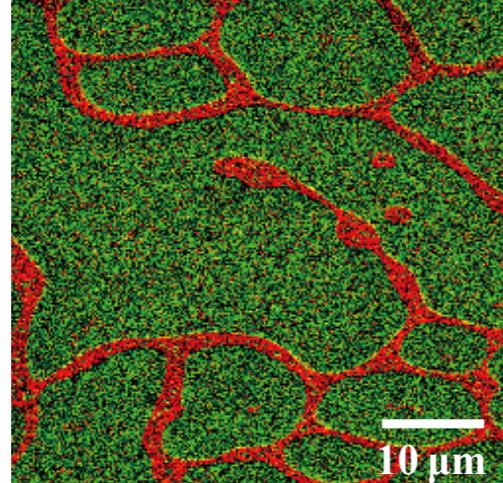


*257nm fs Laser

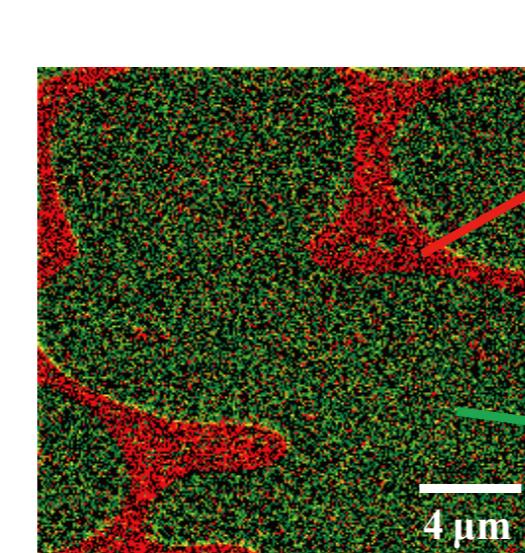
Laser SNMS analysis



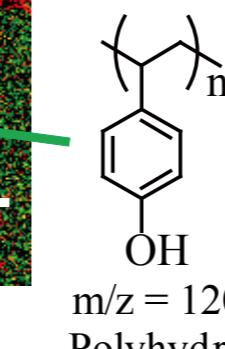
Total ion image



Red; m/z = 104 PS, Green; m/z = 120 PHS



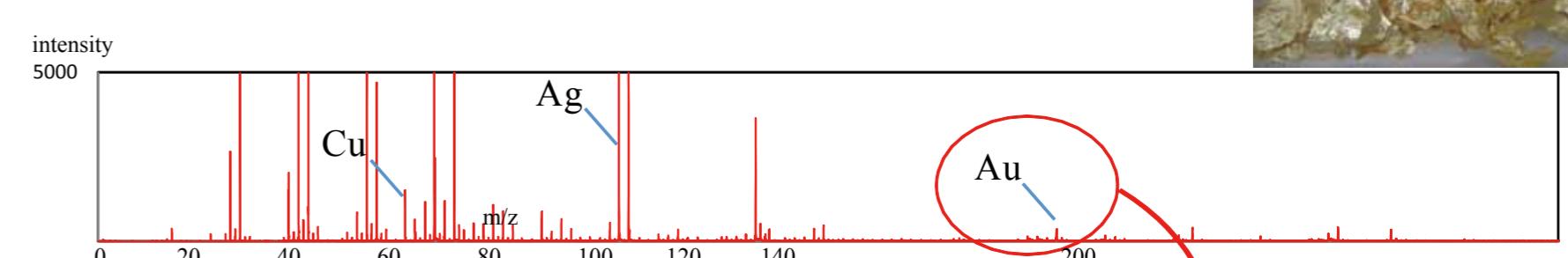
m/z = 104 polystyrene



m/z = 120 Polyhydroxy styrene

Detection Yields Up !! by Laser SNMS

Positive ion SIMS m/z = 0 ~ 300



A few metal elements can hardly be ionized by Ga FIB-SIMS



180 times Larger

While using Lase SNMS ...

